

IPI80N04S4L-04, IPP80N04S4L-04

Parameter	Symbol Conditions	Conditions	Values			Unit
			min.	typ.	max.	

Thermal resistance, junction - case	$R_{ m thJC}$	-	-	-	2.1	K/W
Thermal resistance, junction - ambient, leaded	R _{thJA}	-	-	-	62	
SMD version, device on PCB	R _{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0V, <i>I</i> _D = 1mA	40	-	-	V
Gate threshold voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , / _D =35µA	1.2	1.7	2.2	
Zero gate voltage drain current	I _{DSS}	V _{DS} =40V, V _{GS} =0V	-	0.02	1	μA
		$V_{\rm DS}$ =18V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =85°C ²⁾	-	1	20	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =4.5V, <i>I</i> _D =40A	-	5.1	6	mΩ
		V _{GS} =4.5V, <i>I</i> _D =40A, SMD version	-	4.8	5.7	
		V _{GS} =10 V, <i>I</i> _D =80 A	-	3.7	4.3	
		V _{GS} =10 V, / _D =80 A, SMD version	-	3.4	4.0	



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Dynamic characteristics²⁾

Input capacitance	C _{iss}	V _{GS} =0V, V _{DS} =25V, f=1MHz	-	3610	4690	pF
Output capacitance	Coss		-	650	840	
Reverse transfer capacitance	C _{rss}		-	30	69	
Turn-on delay time	t _{d(on)}		-	7	-	ns
Rise time	t _r	V _{DD} =20V, V _{GS} =10V, I _D =80A, R _G =3.5Ω	-	12	-	
Turn-off delay time	$t_{d(off)}$		-	22	-	
Fall time	t _f		-	31	-	

Gate Charge Characteristics²⁾

Gate to source charge	Q _{gs}		-	12	16	nC
Gate to drain charge	Q _{gd}	V _{DD} =32V, / _D =80A,	-	5	12	
Gate charge total	Qg	V _{GS} =0 to 10V	-	46	60	
Gate plateau voltage	V _{plateau}		-	3.2	-	V

Reverse Diode

Diode continous forward current ²⁾	I _s		-	-	80	А
Diode pulse current ²⁾	I _{S,pulse}	/ _C -23 C	-	-	320	
Diode forward voltage	$V_{\rm SD}$	V _{GS} =0V, / _F =80A, 7 _j =25°C	-	0.9	1.3	V
Reverse recovery time ²⁾	t _{rr}	V _R =20V, / _F =50A, d <i>i</i> _F /d <i>t</i> =100A/µs	-	39	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	35	-	nC

¹⁾ Current is limited by bondwire; with an R_{thJC} = 2.1K/W the chip is able to carry 98A at 25°C.

²⁾ Defined by design. Not subject to production test.

 $^{3)}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



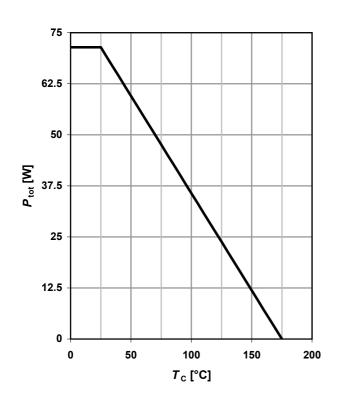
IPI80N04S4L-04, IPP80N04S4L-04

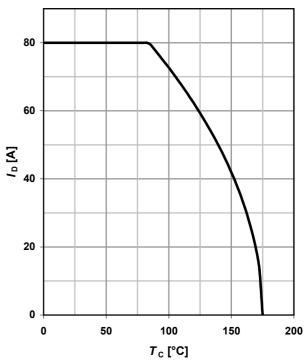
1 Power dissipation

 $P_{tot} = f(T_C); V_{GS} \ge 6 V$

2 Drain current

 $I_{\rm D} = f(T_{\rm C}); V_{\rm GS} \ge 6 \text{ V}; \text{ SMD}$

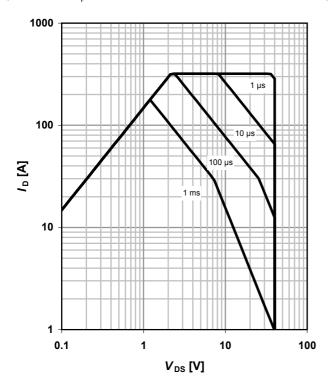




3 Safe operating area

$$I_{\rm D} = f(V_{\rm DS}); T_{\rm C} = 25 \,^{\circ}\text{C}; D = 0; \text{SMD}$$

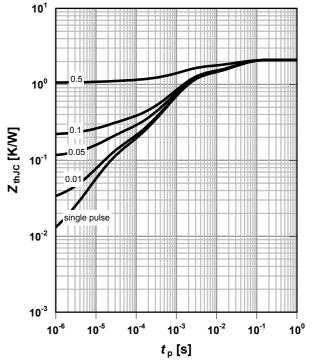
parameter: t_p



4 Max. transient thermal impedance

 $Z_{\rm thJC} = f(t_{\rm p})$

parameter: $D = t_p/T$



Rev. 1.0



parameter: V_{GS}

IPB80N04S4L-04

IPI80N04S4L-04, IPP80N04S4L-04

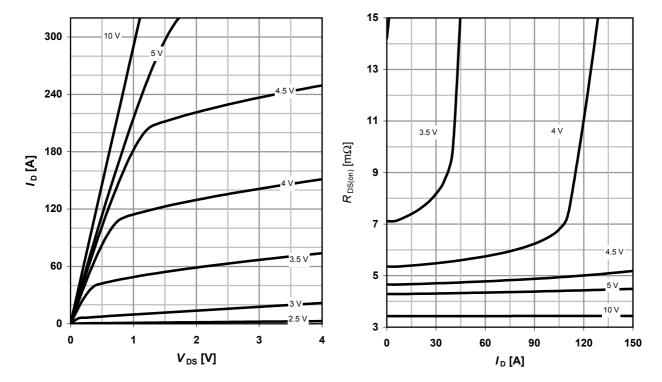
5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm i} = 25 \,^{\circ}\text{C}; \text{SMD}$

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}; \text{SMD}$

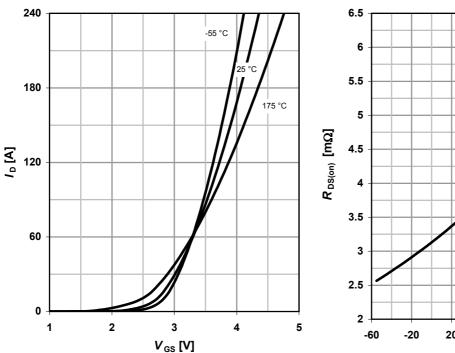
parameter: V_{GS}



7 Typ. transfer characteristics

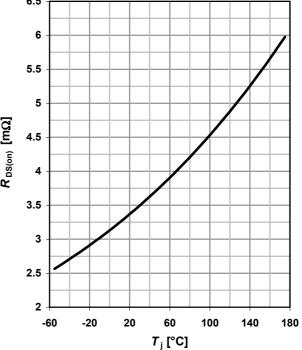
 $I_{\rm D} = f(V_{\rm GS}); V_{\rm DS} = 6V$

parameter: T_j



8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = 80 \text{ A}; V_{GS} = 10 \text{ V}; \text{ SMD}$



Rev. 1.0



IPI80N04S4L-04, IPP80N04S4L-04

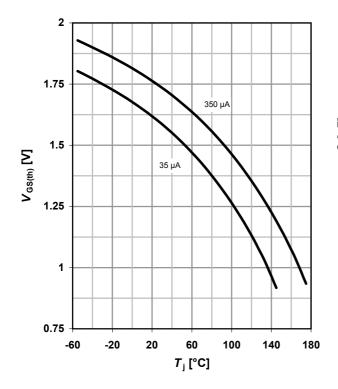
9 Typ. gate threshold voltage

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

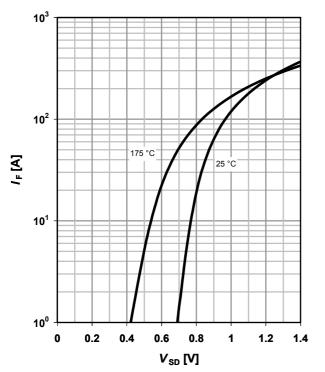
parameter: $I_{\rm D}$



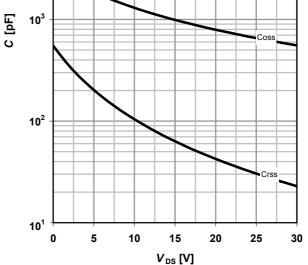
11 Typical forward diode characteristicis

 $IF = f(V_{SD})$

parameter: T_j



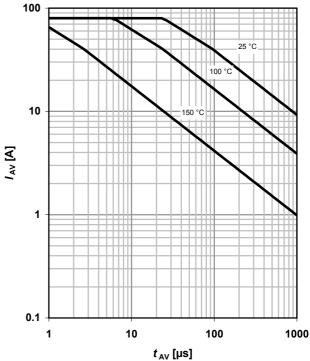
10⁴ L0³



12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}





IPI80N04S4L-04, IPP80N04S4L-04

14 Drain-source breakdown voltage

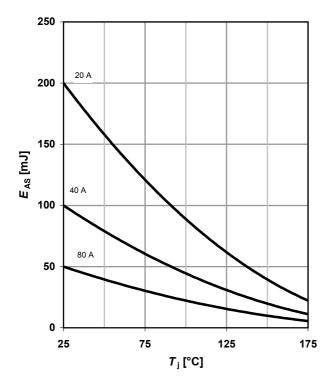
 $V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$

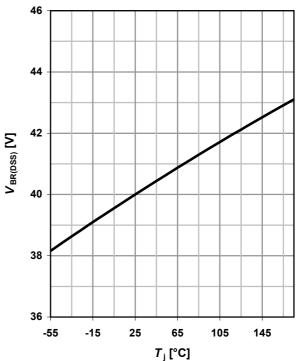
16 Gate charge waveforms

13 Avalanche energy

 $E_{AS} = f(T_i)$

parameter: I_D

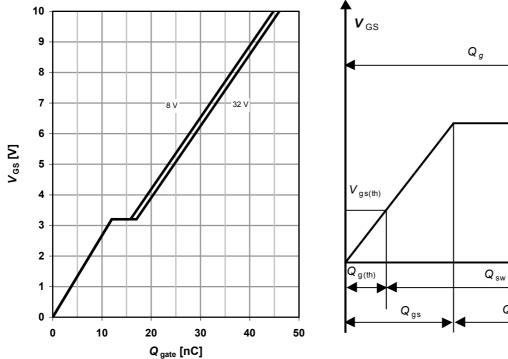


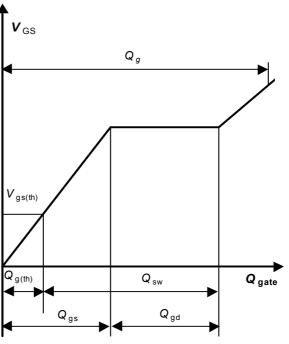


15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 80 \text{ A pulsed}$

parameter: V_{DD}







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IPI80N04S4L-04, IPP80N04S4L-04

Revision History

Version	Date	Changes
Revision 1.0	14.04.2010	Final Data Sheet